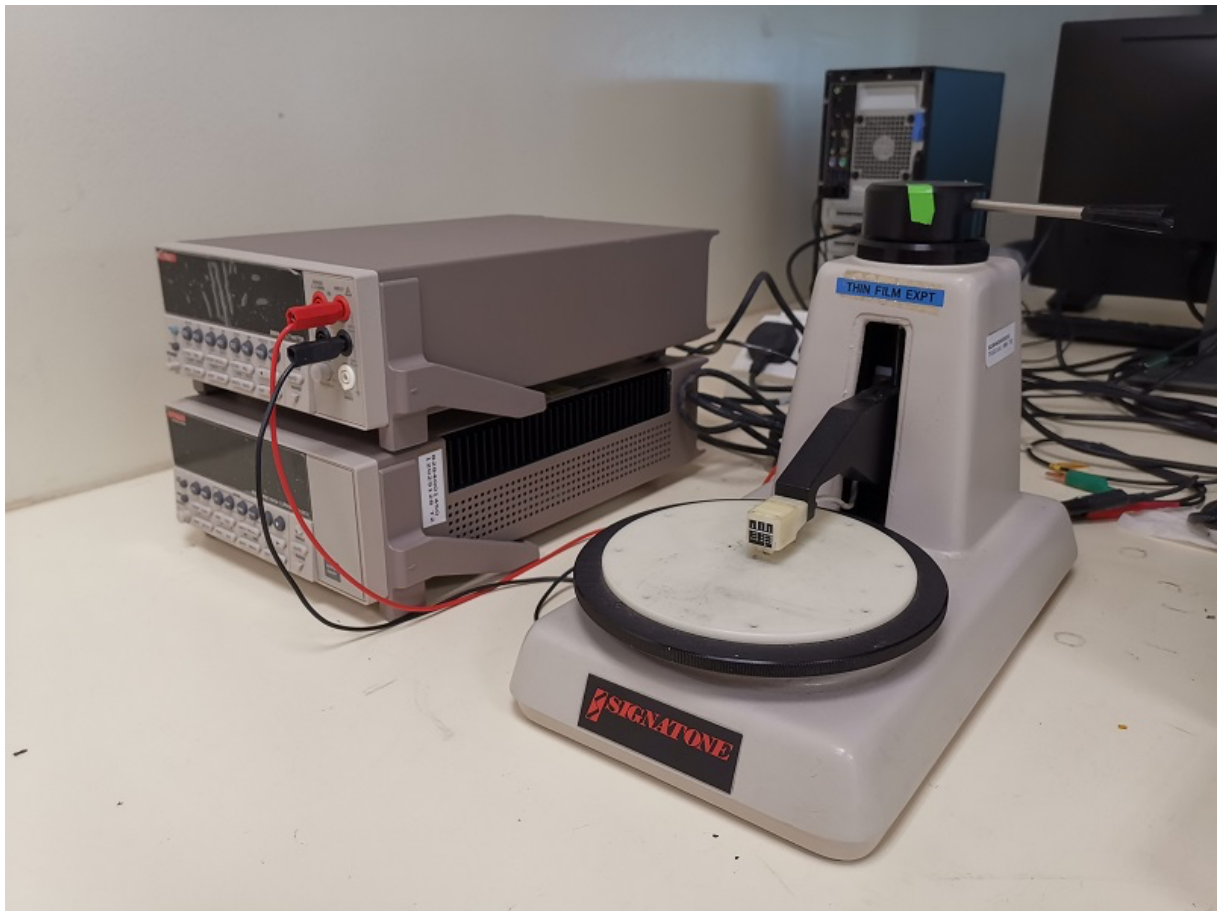


Four point probe



Four point probe is used to measure resistive properties of semiconductor wafers and thin films.